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High resolution transmission electron microscopy -

High resolution transmission electron microscopy of defect clusters in aluminum during electron and ion irradiation at room temperature

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Papers on Applications - Materials Science & -

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High resolution electron microscopy of -

In the present work we discuss some of the applications of High Resolution Electron Microscopy MATERIALS 173 Figure 2. High resolution Proceedings of 51st

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Digital Imaging | Gatan, Inc -

There are a number of options and technologies available for digital imaging in transmission electron microscopy applications today. Traditionally, high energy

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David McComb | Materials Science and Engineering -

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Xinghang Zhang | Texas A&M University | Papers - -

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